



Report No.:

EMC 1907077

File reference No.: 2019-07-05

Applicant:

Product: Brand

Charging Cable

Name:

NA

Model No.:

RC04

Test Standards:

EN 55032:2015

EN61000-3-2:2014

EN 55024: 2010+A1:2015

EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted samples and found in compliance with council EMC Directive

2014/30/EU.

Approved By

Terry Tang

Manageratifica

Dated:

July 05, 2019

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519, 5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen, Guangdong China

Tel (755) 83448688

Fax (755) 83442996

Email: info@timeway-lab.com

Date: 2019-07-05



Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

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The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

FCC-Registration No.: 899988

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.:899988.

IC- Registration No.: IC5205A-01

The EMC Laboratory has been registered and fully described in a report filed with the (IC) Industry Canada. The acceptance letter from the IC is maintained in our files. Registration No.: IC 5205A-01.

VCCI- Registration No.: R-3015 and C-3332

The EMC Laboratory has been registered and fully described in a report filed with the (VCCI) Voluntary Control Council for Interference. The acceptance letter from the VCCI is maintained in our files. Registration IC No.: R-3015 and C-3332

Date: 2019-07-05



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6.0 Product Labelling 39

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1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

1.2 Applicant Details

Applicant:

Address:

Telephone:

Fax:

Manufacturer:

Address:

Telephone:

Fax:

1.3 Description of EUT

Product: Charging Cable

Brand Name: N/A

Model Number: RC04

Rating: Input: 5V

Remark: ---

1.4 Submitted Sample(s)

1 Sample

1.5 Test Duration

2019-06-25 to 2019-07-05

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1.6 Additional information of EUT

	Submitted	Not Available
User Manual	\boxtimes	
Part List		
Circuit Diagram	\boxtimes	
Printed circuit board[PCB] Layout	\boxtimes	
Block Diagram		

1.7 Test Engineer

The sample(s) tested by

Print Name

This test report is not valid without personnel's signatures of SHEN THEN TIMEWAY TESTING LABORATORIES

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2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2018.07.13	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2018.07.13	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2018.07.13	1Year
LISN	ESH3-Z5	100294	RS	2018.07.13	1Year
LISN	ESH3-Z5	100253	RS	2018.07.13	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2018.07.13	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2018.07.13	1Year
Amplifier	8447D	2727A05017	HP	2018.07.13	1Year
Bilog Antenna	VULB9163 91	63/340 Schwarel	oeck	2018.07.13	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2018.11.10	1Year
5K VA AC Power Source	5001iX	56060	CI	2018.11.10	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2018.07.10	1Year

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2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2018.07.13	1Year
Power Meter	NRVS		RS	2018.07.13	1Year
Voltage Probe	URV5-Z2	100012	RS	2018.07.13	1Year
Voltage Probe	URV5-Z2	100013	RS	2018.07.13	1Year
Power Amplifier	150W1000	300999	AR	2018.07.13	1Year
Power Amplifier	25S1G4AM1	305993	AR	2018.07.13	1Year
Field Probe	CBL6111C	2576	Holaday	2018.07.13	1Year
Bilog Antenna	MCDC		Chase	2018.07.13	1Year

Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2018.07.13	1Year
Power Source	MV2616	0104-14	EM TEST	2018.07.13	1Year

2.7 Surge Test

Name	Model No.	Serial No.	Manufacturer	Calibration Date	Calibration Cycle
Ultra Compact	UCS 500			2018.07.13	
Simulator	M4	0304-42	EM TEST	2016.07.13	1Year
Power Source	MV2616	0104-14	EM TEST	2018.07.13	1Year

2.8 Conducted Immunity Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	CWS 500C	0407-05	EM TEST	2018.07.13	1 Year

Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave	LICE 500 MA	0304-42		2010 07 12	
Simulator	imulator UCS 500 M4		EM TEST	2018.07.13	1 Year
Power Source	MV 2616	0104-14		2018.07.13	
Network	MV 2616	0104-14	EM TEST	2010.07.13	1 Year
Current Transformer	MC2630		EM TEST	2018.07.13	1 Year

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Magnetic Coil	MS100	0304-42	EM TEST	2018.07.13	1 Year

2.10 Voltage Dips/Interruption Immunity Test

	1	,			
				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact				2018.07.13	
Simulator	UCS 500 M4	0304-42	EM TEST	2018.07.13	1Year
Power Source	MV2616	0104-14	EM TEST	2018.07.13	1Year

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Technical Details 3.0

Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility [EMS] tests for CE Marking

3.2 Test Standards

_	Test Standards						
EN 55032:2015	Electromagnetic compatibility of multimedia equipment - Emission Requirements						
ENG1000 2 2 2014	Electromagnetic compatibility(EMC)-	Electromagnetic compatibility(EMC)- Part 3-2:Limits-Limits for harmonic current					
EN61000-3-2:2014	emissions(equipment input current ≤	16A per phase)					
	Electromagnetic compatibility (EMC)- Part 3-3:Limits-Limitation of voltage						
EN 61000 2 2,2012	changes, Voltage fluctuations and flicker in public low-voltage supply systems. For						
EN 61000-3-3:2013	equipment with rated current ≤16A per phase and not subject to conditional						
	connection						
EN	Information technology equipment — Immunity characteristics — Limits and						
55024:2010+A1:2015	methods of measurement						
	EN 61000-4-2:2009	Electrostatic discharge					
	EN 61000-4-3:2006	RF field strength susceptibility					
	EN 61000-4-4:2012	Electrical Fast transients					
	EN 61000-4-5:2014	Surge					
	EN 61000-4-6:2009	Conducted susceptibility					
	EN 61000-4-8:2010	Power-frequency Magnetic Field					
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation					

Performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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3.4 Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result
	EMISSION Results Summ	nary	
Conducted Emission on AC Mains,	EN 55032:2015	EN 55032:2015	N/A
150KHz to 30MHz			IN/A
Conducted Emission on at	EN 55032:2015	EN 55032:2015	
telecommunication ports,			N/A
150KHz to 30MHz			
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass
30MHz to 1GHz			1 ass
Harmonic Emissions on AC supply	EN61000-3-2:2014	EN61000-3-2:2014	N/A
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A
	IMMUNITY Results Sum	mary	
Electrostatic Discharge	EN 55024: 2010+A1:2015	EN 61000-4-2: 2009	Pass
Electrical Fast transients	EN 55024: 2010+A1:2015	EN 61000-4-4: 2012	N/A
/Burst Immunity			IN/A
RF field strength susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-3: 2006	Pass
Surge	EN 55024: 2010+A1:2015	EN 61000-4-5: 2014	N/A
Conducted susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-6: 2009	N/A
Power-frequency Magnetic Field	EN 55024: 2010+A1:2015	EN61000-4-8: 2010	N/A
Dips/Voltage Interruption Variation	EN 55024: 2010+A1:2015	EN 61000-4-11: 2004	N/A

Note: N/A-Not applicable

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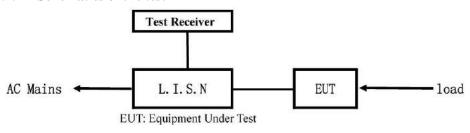


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4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

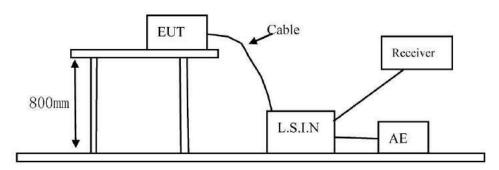
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(μ V)						
Frequency(MHz)	Class A E	quipment	Class B Equipment				
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level			
0.15 ~ 0.50	79.0	66.0	66.0~56.0*	56.0~46.0*			
0.50 ~ 5.00	73.0	60.0	56.0	46.0			
5.00 ~ 30.00	73.0	60.0	60.0	50.0			

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=3.6dB

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Conducted Emission on Live Terminal (150kHz to 30MHz) A:

EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

EUT set Condition: Charging Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

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B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

EUT set Condition: Charging Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

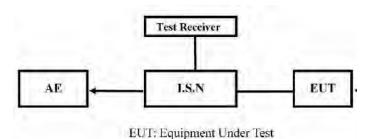
Date: 2019-07-05



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Telecommunication ports Conducted Emission Test 4.2

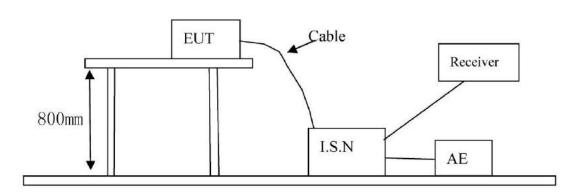
Schematics of the test



4.2.2 **Test Method:**

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



Telecommunication ports conducted Emission Limit

	Class A Limits			Class B Limits				
Frequency(MHz)	Quasi-pe	eak Level	Averag	e Level	Quasi-peak Level Average		ge Level	
requency(wirtz)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)
0.15 ~ 0.50	97 to 87	53 to43	84 to 74	40 to 30	84 to 74	40 to30	74 to 64	30 to 20
0.50 ~ 30.00	87	43	74	30	74	30	64	20

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

4.2.4 **Test Results**

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

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A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBµV)		Limit(dBµV)	
(MHz)	Polt	Quasi-peak	Average	Quasi-peak	Average
	LAN				
	LAN				

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B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

EUT set Condition: Normal operation mode

Equipment Level: ClassB

Results: N/A

Please refer to following diagram for individual

Frequency	Dort	Port Reading(dBµA)		Limit(dBµA)	
(MHz)	Fort	Quasi-peak	Average	Quasi-peak	Average
	LAN				

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4.3 Radiated Disturbance Test

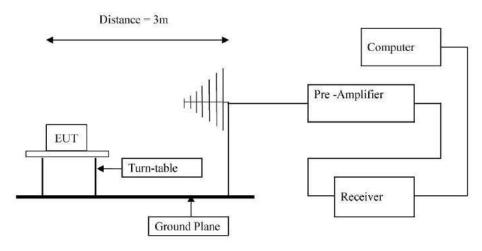
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB μ V/m)	
	Class A Limits	Class B Limits
30-230	50.00	40.00
230-1000	57.00	47.00

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

Date: 2019-07-05



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A: Radiated Disturbance (30MHz----1000MHz)

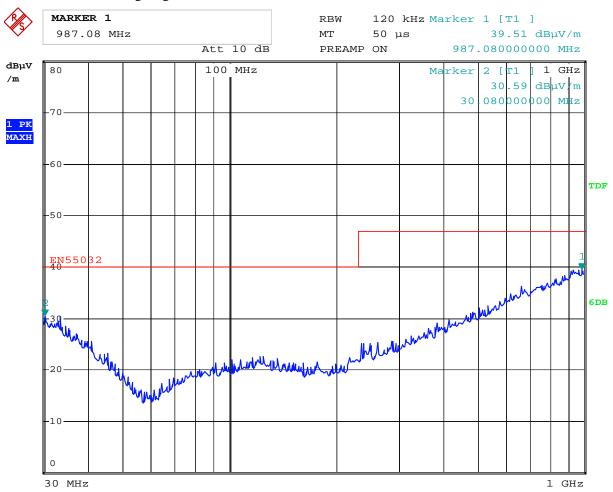
EUT Operating Environment

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



Date: 29.July .2019 14:30:12

Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
987.080	39.51	Н	47.00
30.080	30.59	Н	40.00

The report refers only to the sample tested and does not apply to the bulk.

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B: Radiated Disturbance (30MHz----1000MHz)

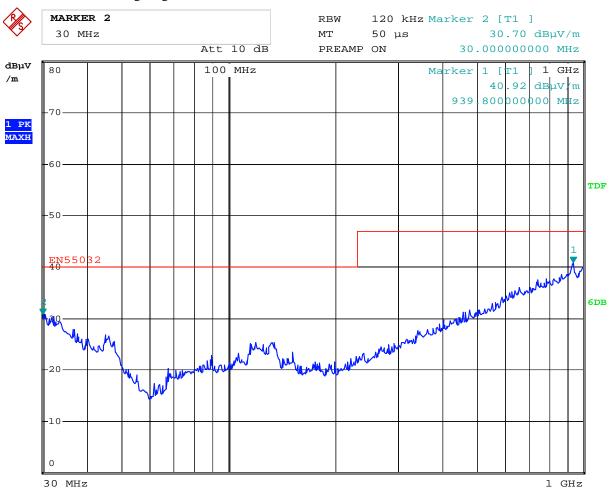
EUT Operating Environment

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



Date: 29.July .2019 14:39:20

Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
30.000	30.70	V	40.00
939.800	40.92	V	47.00

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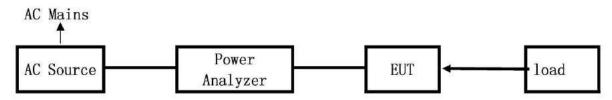
Date: 2019-07-05



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4.4 Harmonic Current Emission Test

4.4.1 Schematic of the test



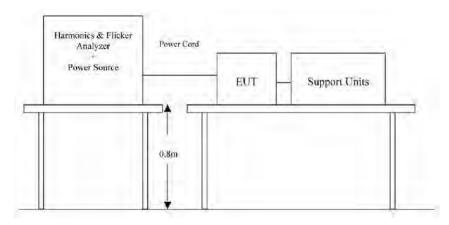
EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2014

*: The Level of the product is : CLASS D

Block diagram of Test setup



4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current
n	A
Odd h	armonics
3	2,30
5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
$15 \le n \le 39$	0.15 15 n
Even h	armonics
2	1,08
4	0,43
6	0,30
$8 \le n \le 40$	0,23 8 n

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4.4.4 Test Results



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Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

EUT set Condition:

Results: N/A

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

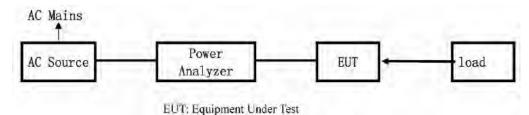
Date: 2019-07-05



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4.5 Voltage Fluctuations & Flicker Test

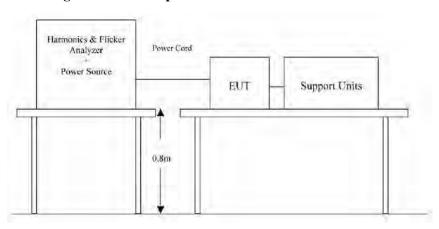
4.5.1 Schematic of the test



4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

Block diagram of Test setup



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4.5.3 Test Results

Result: N/A

Please refer to following diagram for individual

Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

Date: 2019-07-05

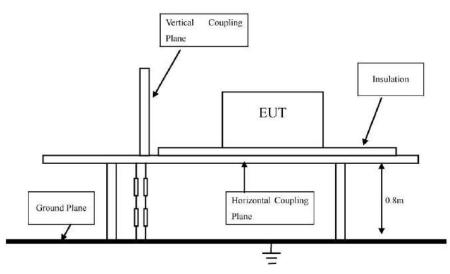


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5.0 Immunity Test

5.1 Electrostatic Discharge

5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- ± 8 Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	±4Kv	±4Kv
3	±6Kv	±8Kv
4	±8Kv	±15Kv

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5.1.5 Test Result

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

Location Discharge Method Test Voltage F					
Location	Discharge Method	Test Voltage	Results		
НСР	In-Direct	± 2 Kv, ± 4 Kv	Pass		
VCP	In-Direct	± 2 Kv, ± 4 Kv	Pass		
Shell (metal)	Contact Discharge	± 2 Kv, ± 4 Kv	Pass		
Screw	Contact Discharge	± 2 Kv, ± 4 Kv	Pass		
Function key	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass		
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass		

Remark: Calculated measurement uncertainty= 0.2kV

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5.2 RF field strength susceptibility (80MHz----- 1000MHz)

5.2.1 Schematics of the test



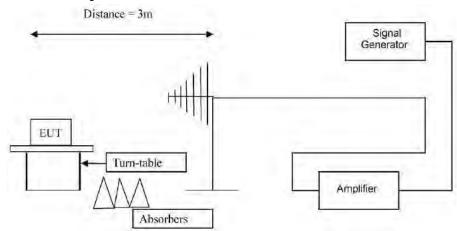
5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

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5.2.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency (MHz)	Face	Polarity	Level (V/m)	Dwell Time(s)	Sweep Rate (%)	Results
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/ -1.3) V/m

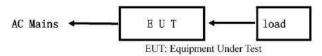
Date: 2019-07-05



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5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



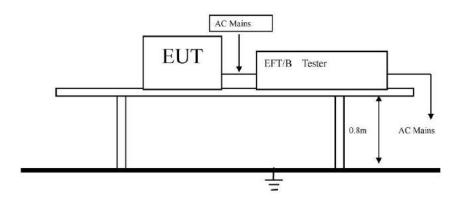
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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5.3.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage	Inject	Method	Results
	kV	Times (s)		
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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5.4 Surge test

5.4.1 Schematics of the test



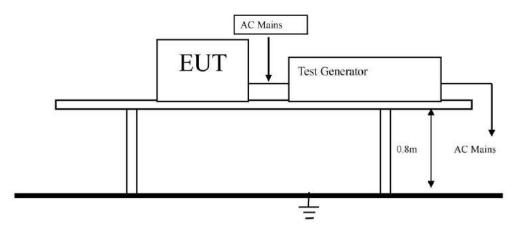
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

Severity Level	Open-Circuit Test Voltage
	kV
1	0.5
2	1.0
3	2.0
4	4.0
*	Special

5.4.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	Pass
T NI	±	90	5	1.0	Pass
L-N	±	180	5	1.0	Pass
	土	270	5	1.0	Pass

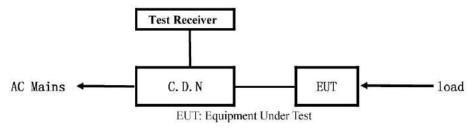
Date: 2019-07-05



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5.5 Conducted Immunity test

5.5.1 Schematics of the test



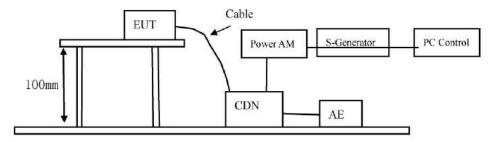
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V	
1	1	
2	3	
3	10	
*	Special	

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5.5.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Thease feler to the following page					
Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	Pass
20 - 80	AC Line	3V (rms) Unmodulated	A	A	Pass

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5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



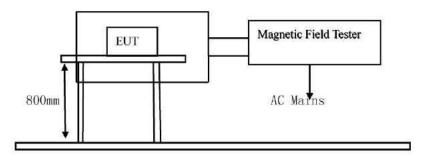
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
*	Special

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5.6.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Test Level	Testing Duration	Coil Orientation	Criterion	Result		
1A/m	5 Mins	X	A	N/A		
1A/m	5 Mins	Y	A	N/A		
1A/m	5 Mins	Z	A	N/A		

Date: 2019-07-05

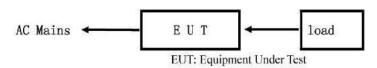


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5.7 Voltage Dips/Interruptions immunity test

5.7.1 Schematics of the test

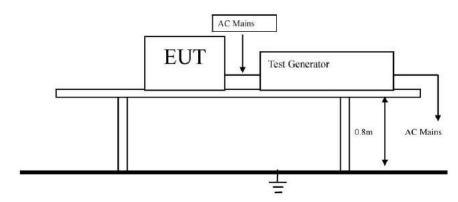


5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

	Test Level %Ut	Reduction	Duration	Performance	
Voltage			(Periods)	Criteria	
Dip	<5	>95	0.5	В	
	70	30	25	C	
X7-14	Test Level %Ut	Reduction	Duration	Performance	
Voltage			(Periods)	Criteria	
Interceptions	<5	>95	250	C	

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Voltage Dip:

Ī	Test Level	Reduction	Duration	Phase Angle	Meet	Result
	% Ut		(periods)		Criterion	
	0	100	0.5	0° - 360°	A	Pass
	70	30	25	0° - 360°	A	Pass

Voltage Interceptions:

t Level 6 Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	В	Pass

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6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

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Photo for the EUT





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Photo for the EUT



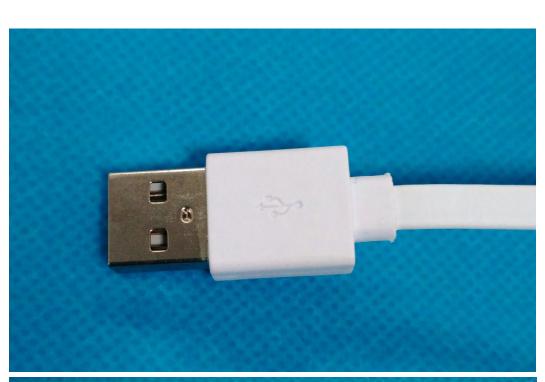


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Photo for the EUT





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